

File No.: 9-16313-2US

February 11, 2004

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**Applicant:** Mark F. ELDRIDGE  
**Serial No.:** New Application  
**Filed:** New Application  
**Title:** THERMAL MASS FLOWMETER APPARATUS AND  
METHOD WITH TEMPERATURE CORRECTION  
**Agent of Record:** Paul S. Sharpe Tel: (613) 780-8676

-----  
**Mail Stop DD**  
Commissioner for Patents  
United States Patent and Trademark Office  
P.O. Box 1450  
Alexandria, VA 22313-1450  
U.S.A.

Sir:

**INFORMATION DISCLOSURE STATEMENT**  
**PRIOR TO FIRST OFFICE ACTION**

Pursuant to the duty of disclosure under 37 CFR 1.56, copies of the references (other than U.S. patents and U.S. published applications) listed on the attached PTO Form 1449 are submitted herewith.

The Examiner is kindly requested to consider these references during the examination of the above-identified application, making the references of record, and to return an initialed copy of the PTO-1449 Form to the below-signed agent.

In accordance with 37 CFR 1.97(h), the submission of the present information is not to be construed as an admission that such information is, or is considered to be material to patentability.

Respectfully submitted,

By: 

AGENT, Registration No. 39,493  
OGILVY RENAULT  
1600 - 1981 McGill College Avenue  
Montreal, Quebec, Canada H3A 2Y3

Encls.

Form PTO-1449 (Rev.7-80)	U.S. Department of Commerce Patent & Trademark Office	ATTY. DOCKET NO. 9-16313-2US	SERIAL NO. New Application
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Mark F. Eldridge	
		FILING DATE: New Application	GROUP New Application

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
	AA	3,366,942	Jan 30, 1968	R.A. Deane	340	243	July 21, 1966
	AB	4,475,388	Oct.9, 1984	Kawai et al.	73	204	Oct. 7, 1982
	AC	5,237,523	Aug. 17, 1993	Bonne et al.	364	571.03	July 25, 1990
	AD	5,544,531	Aug. 13, 1996	Heckman	73	861.01	Jan. 9, 1995
	AE	5,913,250	June 15, 1999	Wible	73	861.65	Oct. 29, 1997
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		Document number	Date	Country	Class	Subclass	Translation
	AL						
	AM						
	AN						
	AO						
	AP						

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	
	AS	
	AT	

Examiner	Date considered
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	